FLEX[™] Microscope Spectrophotometer

Economical UV-Visible-NIR Microspectroscopy.

ECHNOLOGIES

FLEXTM from CRAIC Technologies is an economical yet powerful UV-Visible-NIR microspectrophometer. It is able to non-destructively measure the absorbance, reflectance, and fluorescence spectra of sample areas on the micron scale.

The **FLEX[™]** microscope spectrophotometer is as flexible as its name implies. **FLEX[™]** is able to measure spectra of microscopic samples from the deep UV to the near IR in one shot. Designed for flexibility and economy, this instrument pushes the boundaries of scientific and industrial microspectroscopy. It is able to analyze everything from a single textile fiber in a forensic case to microdisplay from a TFT manufacturer. This instrument is equally at home in the lab and the factory.

The **FLEX[™]** microscope spectrophometer features sensitive CCD array detectors mounted to a pre-aligned spectrophotometer. Each detector can be TE cooled to achieve low noise and long term stability. This results in an instrument with a superior signal-to-noise ratio. Included is a UV-visible-NIR range microscope, a high-resolution color digital imaging system, UV-shielded eyepieces, a computer running Windows 7 Professional, and an integrated spectral analysis/instrument control software package. **FLEX[™]** is easy to use, durable and will provide cutting-edge results.

Applications: • Trace Evidence • Flat Panel Display Color Masks • Flat Panel Light Sources • Questioned Documents • Surface Plasmon Resonance • OLED • Semiconductor Film Thickness

FLEX [™] Specifications	
Transmission Microspectra™	240 to 900 nm
Reflectance Microspectra™	240 to 900 nm
Fluorescence Microspectra [™]	400 to 900 nm
Fluorescence Excitation	365 to 546 nm
Sampling Area	Variable from 1 to 10000 microns ²
Spectral Bandwidth	0.32 nm
Detector	CCD Array
Detector Cooling	Thermoelectric Offered
Scan Time (Full Range)	4 millisecond minimum
High Resolution Digital Imaging	Up to 5 Megapixel
Glass Refractive Index	Offered
Operating System	Windows 7







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Calibration Standards System Software Transmittance Standards Traceable to NIST SRMS Spectral Database

- Reflectance Standards Traceable to NIST SRMS
- Diffuse Reflectance Standard Traceable to NIST SRMS
- Uitrinite Coal Reflectance Standards
- Colorimetry **General Statistical Analysis** □ CRAIC CoalPro[™]

Accessories

- Quartz Slides and Coverslips Replacement Bulbs
- UV-Visible-NIR Microplate Wells Specular Reflectance Material
- Computer Monitor

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